

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 230421US26YA		SERIAL NO. 10/673,501	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Andrej S. MITROVIC			
				FILING DATE September 30, 2003		GROUP 2128	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	US 2005-0071037	3/31/2005	Strang			
	AB	US 2005-0071035	3/31/2005	Strang			
	AC	US 2005-0071038	3/31/2005	Strang			
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	AF	US 6,198,980 B1	3/2001	Costanza, John R.			
	AG	US 7,107,571 B2	9/2006	Chang, et al.			
	AH	US 5,741,070	4/21/1998	Mehrdad Mahmud Moslehi			
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	AN	US 5,377,116	12/1994	Wayne, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	CN 1335558A	2/13/2002	China (with Partial English Translation)	X		
	AP	WO 02/07210 A2	1/24/2002	WIPO			X
	AQ	EP 0 718 595 A2	6/26/1996	EUROPE			X
	AR	JP 2004-527117	9/2/2004	Japan (Corresponding to WO 02/077589 A2 and A3)			X
	AS	WO 03/060779 A1	7/24/2003	WIPO			X
	AT	JP 2005-515623	5/26/2005	JAPAN (With English Abstract)			X
	AU	WO 03/009345 A2	1/30/2003	WIPO			X
	AV	JP 2005-522018	7/21/2005	JAPAN (With English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Naomi YONEMURA, et al. "Heat Analysis on Insulated Metal Substrates", 1996, IEEE, pgs. 1407-1410					
	AX	Heru SETYAWAN, et al. "Visualization and numerical simulation of fine particle transport in a low-pressure parallel plate chemical vapor deposition reactor", Chemical Engineering Science 57 (2002) pages 497-506					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Andrej S. MITROVIC

FILING DATE

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2128

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	AAA	US 5,629,877	5/1997	Tamegaya, Yukio			
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	AAF						
	AAG						
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	AAK						
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	AAN						

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AAO	JP 2003-17471	1/17/2003	JAPAN (With English Abstract)		X
	AAP	WO 02/065511 A2	8/22/2002	WIPO		X
	AAQ	JP 2004-524685	8/12/2004	JAPAN (Corresponding to WO 02/065511 A2 and A3)		X
	AAR	WO 02/069063 A2	9/6/2002	WIPO		X
	AAS	JP 2004-531878A	10/14/2004	JAPAN (Corresponding to WO 02/069063 A2 and A3)		X
	AAT	JP 2000-517473	12/26/2000	JAPAN (With English Abstract)		X
	AAU	WO 03/058699 A1	7/17/2003	WIPO		X
	AAV	JP 2005-514790	5/19/2005	JAPAN (With English Abstract)		X

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	AAW	
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	AAZ	
		<input type="checkbox"/> Additional References sheet(s) attached
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	AAAA						
	AAAB						
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AAAO	JP 2002-367875	12/20/2002	JAPAN (with English Abstract and Computer generated translation only)		X
	AAAP	JP 2003-502771	1/21/2003	JAPAN (with English Abstract and Computer generated translation only)	X	
	AAAQ	WO 02/077589 A2	10/3/2002	WIPO		X
	AAAR	WO 97/21244	12/6/1997	WIPO		X
	AAAS	JP 11-176906	7/2/1999	JAPAN (with English Abstract and Computer generated translation only)	X	
	AAAT					
	AAAU					
	AAAV					
	AAAW					
	AAAX					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AAAY	
	AAAZ	
		<input type="checkbox"/> Additional References sheet(s) attached
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